

# **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	T <sub>C</sub> = 25 °C		1.6	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	T <sub>A</sub> = 25 °C	(Note 1a)	50	C/vv

# Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
09OD	FDMS8558S	Power 56	13"	12 mm	3000 units

1

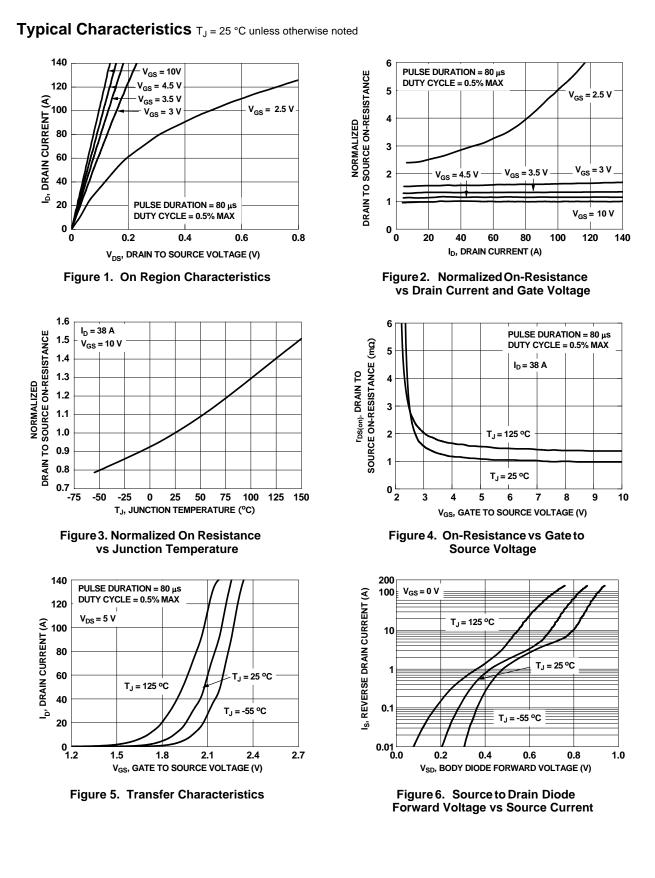
cteristics					
Drain to Source Breakdown Voltage	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0 V	25			V
Breakdown Voltage Temperature Coefficient	$I_D = 10$ mA, referenced to 25 °C		24		mV/°C
Zero Gate Voltage Drain Current	$V_{DS} = 20 V, V_{GS} = 0 V$			500	μA
Gate to Source Leakage Current	$V_{GS} = +12 \text{ V/-8 V}, V_{DS} = 0 \text{ V}$			±100	nA
cteristics					
	$V_{00} = V_{00}$ $l_{0} = 1 \text{ mA}$	1.1	1.4	2.2	V
Gate to Source Threshold Voltage	$I_D = 10 \text{ mA}, \text{ referenced to } 25 \text{ °C}$		-3	2.2	mV/°C
	$V_{CS} = 10 \text{ V}$ . Ip = 33 A		1.1	1.5	
Static Drain to Source On Resistance			1.3	1.7	mΩ
			1.6	2.1	-
Forward Transconductance			317		S
Characteristics					
			5118		pF
	$-V_{DS} = 13 \text{ V}, V_{GS} = 0 \text{ V},$				pF
	f = 1 MHz				pF
					Ω
Characteristics					1
			14		ns
Rise Time	Vpp = 13 V. lp = 33 A.		8		ns
Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$		51		ns
Fall Time			7		ns
Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V		81		nC
Total Gate Charge			38		nC
Gate to Source Gate Charge	I <sub>D</sub> = 33 A		10		nC
Gate to Drain "Miller" Charge	-		9.7		nC
Irce Diode Characteristics			I	I	
	$V_{CS} = 0 V$ , $I_S = 2 A$ (Note 2)		0.6	0.8	
Source to Drain Diode Forward Voltage					V
Reverse Recovery Time			35		ns
Reverse Recovery Charge	— I <sub>F</sub> = 33 A, di/dt = 300 A/μs		49		nC
ined with the device mounted on a FR-4 board using a spec		b) 125 °C/V	by design wh	ted on a	
	Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Source Leakage Current Cteristics Gate to Source Threshold Voltage Gate to Source Threshold Voltage Temperature Coefficient Static Drain to Source On Resistance Forward Transconductance Characteristics Input Capacitance Output Capacitance Output Capacitance Gate Resistance Characteristics Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Total Gate Charge Gate to Source Gate Charge Gate to Drain "Miller" Charge Source to Drain Diode Forward Voltage Reverse Recovery Time Reverse Recovery Charge	Breakdown Voltage Temperature Coefficient Ip = 10 mA, referenced to 25 °C   Zero Gate Voltage Drain Current $V_{DS} = 20$ V, $V_{GS} = 0$ V   Gate to Source Leakage Current $V_{GS} = +12$ V/-8 V, $V_{DS} = 0$ V   Cheristics Gate to Source Threshold Voltage $V_{GS} = +12$ V/-8 V, $V_{DS} = 0$ V   Cate to Source Threshold Voltage Ip = 10 mA, referenced to 25 °C   Fermerature Coefficient Ip = 10 mA, referenced to 25 °C   Static Drain to Source On Resistance $V_{GS} = 10$ V, $I_D = 33$ A   Vasce 4.5 V, Ip = 31 A $V_{GS} = 10$ V, $I_D = 33$ A   Characteristics VDS = 5 V, Ip = 31 A   Input Capacitance $V_{DS} = 13$ V, $V_{GS} = 0$ V,   Output Capacitance $V_{DS} = 13$ V, $V_{GS} = 0$ V,   Gate Resistance VDD = 13 V, ID = 33 A,   Turn-On Delay Time $V_{GS} = 0$ V to 10 V   Rise Time $V_{GS} = 0$ V to 10 V   Total Gate Charge $V_{GS} = 0$ V to 4.5 V   Gate to Source Gate Charge $V_{GS} = 0$ V, $I_S = 33$ A   Ince to Drain Diode Forward Voltage $V_{GS} = 0$ V, $I_S = 33$ A   Reverse Recovery Time $I_F = 33$ A, di/dt = 300 A/µs   Reverse Recovery Charge $I_F = 33$ A, di/dt = 300 A/µs	Breakdown Voltage Temperature Coefficient $I_b = 10 \text{ mA}$ , referenced to 25 °C   Zero Gate Voltage Drain Current $V_{DS} = 20 \text{ V}$ , $V_{GS} = 0 \text{ V}$ Gate to Source Leakage Current $V_{GS} = 112 \text{ V/-8} \text{ V}$ , $V_{DS} = 0 \text{ V}$ certristics Image: Coefficient $V_{GS} = 112 \text{ V/-8} \text{ V}$ , $V_{DS} = 0 \text{ V}$ Gate to Source Threshold Voltage $I_b = 10 \text{ mA}$ , referenced to 25 °C Image: Coefficient   Static Drain to Source On Resistance $V_{GS} = 10 \text{ V}$ , $I_D = 33 \text{ A}$ Image: Coefficient   Vags = 10 V, $I_D = 33 \text{ A}$ V_{CS} = 10 V, $I_D = 33 \text{ A}$ Image: Coefficient   Static Drain to Source On Resistance $V_{GS} = 10 \text{ V}$ , $I_D = 33 \text{ A}$ Image: Coefficient   Vags = 10 V, $I_D = 33 \text{ A}$ V_{CS} = 10 V, $I_D = 33 \text{ A}$ Image: Coefficient   Output Capacitance Image: Coefficient V_{DS} = 5 V, $I_D = 33 \text{ A}$ Image: Coefficient   Input Capacitance Image: Coefficient V_{DS} = 13 V, $V_{CS} = 0 \text{ V}$ Image: Coefficient   Input Capacitance Image: Coefficient V_{DS} = 13 V, $V_{CS} = 0 \text{ V}$ Image: Coefficient   Input Capacitance Vags = 10 V, R_{GEN} = 6 \Omega Image: Coefficient Image: Coefficient   Itrun-Off Delay Time Vags = 0 V to 10 V	Breakdown Voltage Temperature Coefficient I <sub>D</sub> = 10 mA, referenced to 25 °C 24   Cate to Source Drain Current V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V 1   Gate to Source Leakage Current V <sub>GS</sub> = +12 V/-8 V, V <sub>DS</sub> = 0 V 1   Chefficient V <sub>GS</sub> = +12 V/-8 V, V <sub>DS</sub> = 0 V 1   Chefficient V <sub>GS</sub> = 10 V, I <sub>D</sub> = 33 A 1.1   Gate to Source Threshold Voltage I <sub>D</sub> = 10 mA, referenced to 25 °C -3   V <sub>GS</sub> = 10 V, I <sub>D</sub> = 33 A 1.1 1.4 1.4   Static Drain to Source On Resistance V <sub>GS</sub> = 10 V, I <sub>D</sub> = 33 A, T <sub>J</sub> = 125 °C 1.6   Forward Transconductance V <sub>DS</sub> = 5 V, I <sub>D</sub> = 31 A 1.3 1.3   VGS = 10 V, I <sub>D</sub> = 33 A, T <sub>J</sub> = 125 °C 1.6 1.6 1.6   Forward Transconductance V <sub>DS</sub> = 5 V, I <sub>D</sub> = 33 A 317   Characteristics   Input Capacitance V <sub>DS</sub> = 13 V, V <sub>GS</sub> = 0 V, 5118   Output Capacitance V <sub>DS</sub> = 13 V, I <sub>D</sub> = 33 A, 8 8   Turn-On Delay Time V <sub>DS</sub> = 0 V to 10 V 144 8   Reverse Transfer Capacitance V <sub>OS</sub> = 0 V to 10 V 81 10   Gate to Source Gate Charge V <sub>GS</sub> = 0 V to 10	Breakdown Voltage Temperature Coefficient I <sub>D</sub> = 10 mA, referenced to 25 °C 24   Zero Gate Voltage Drain Current V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V 500   Gate to Source Leakage Current V <sub>GS</sub> = +12 V/-8 V, V <sub>DS</sub> = 0 V ±100   cteristics Image: Control of the state

2. Pulse Test: Pulse Width < 300  $\mu \text{s},$  Duty cycle < 2.0%.

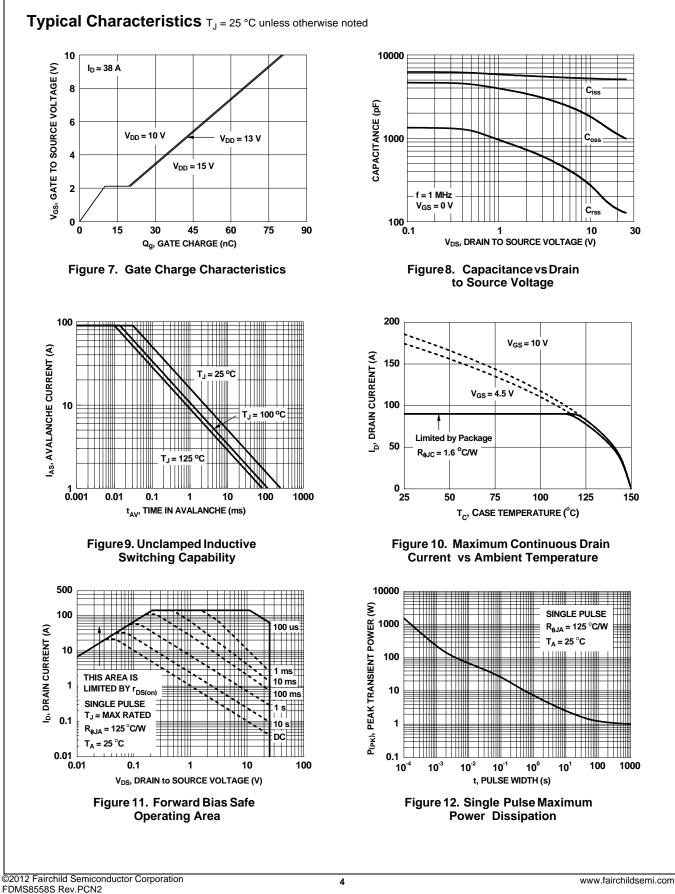
3. E<sub>AS</sub> of 145 mJ is based on starting T<sub>J</sub> = 25 °C, L = 0.9 mH, I<sub>AS</sub> = 18 A, V<sub>DD</sub> = 23 V, V<sub>GS</sub> = 10 V. 100% test at L = 0.1 mH, I<sub>AS</sub> = 39 A.

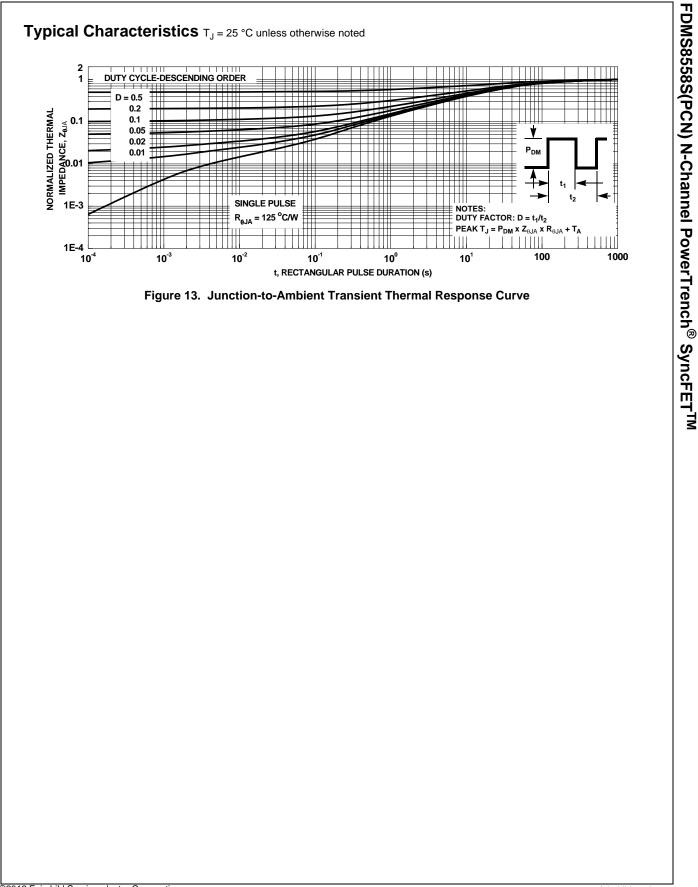
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# Typical Characteristics (continued)

# SyncFET<sup>™</sup> Schottky body diode Characteristics

Fairchild's SyncFET<sup>TM</sup> process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 14 shows the reverse recovery characteristic of the FDMS8558S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

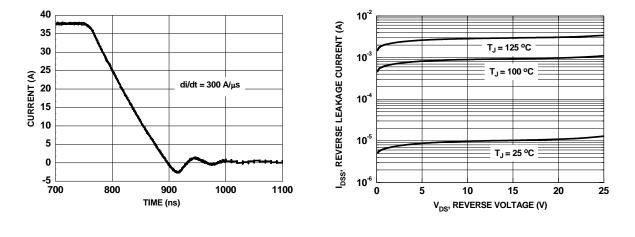
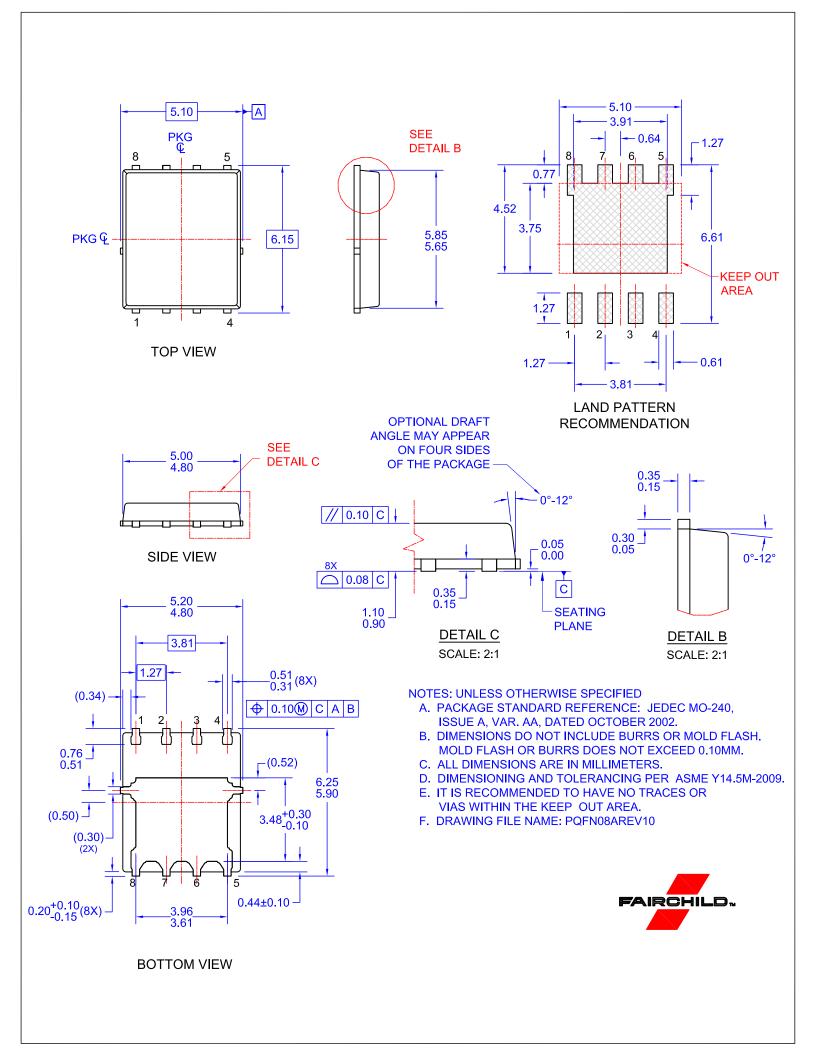


Figure 14. FDMS8558S SyncFET<sup>TM</sup> body diode reverse recovery characteristic

# Figure 15. SyncFET<sup>TM</sup> body diode reverse leakage versus drain-source voltage





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